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JC860 U.S. PTO
09/27/00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)
ANATOLY FABRIKANT ET AL.)
For: IMPROVED SYSTEM FOR)
SCATTEROMETRIC)
MEASUREMENTS AND)
APPLICATIONS)

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San Francisco, California

Patent Application
Assistant Commissioner for Patents
Washington, D.C. 20231

By Express Mail No: EL492667862US
Dated: September 27, 2000

PATENT APPLICATION TRANSMITTAL

Sir:

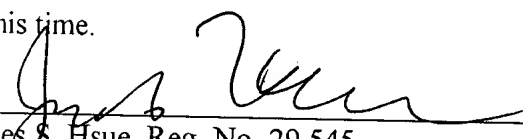
Transmitted herewith for filing is the patent application of inventors ANATOLY FABRIKANT, GUOHENG ZHAO, DANIEL C. WACK and MEHRDAD NIKOONAHAD, for "IMPROVED SYSTEM FOR SCATTEROMETRIC MEASUREMENTS AND APPLICATIONS."

Enclosed are:

1. Fifty (50) pages of the specification, including one-hundred fifteen (115) claims and an abstract.
2. Fourteen (14) sheets of drawings.

The filing fee will be deferred at this time.

Dated: September 27, 2000.


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